

**METHOD OF ALIGNING A SUBSTRATE, COMPUTER
PROGRAM, DEVICE MANUFACTURING METHOD, AND
DEVICE MANUFACTURED THEREBY**

ABSTRACT OF THE DISCLOSURE

5 While the alignment beam is focused on a mark on the substrate table,
the substrate table is moved substantially perpendicularly to the alignment
beam. If the image of the mark moves relative to a reference mark, then the
substrate and the alignment beam are not perpendicular. The mark on the
substrate table is aligned to a plurality of reference marks. At least two
10 substrate marks are then aligned with a single reference mark. Errors due to
the inclination of the alignment beam are eliminated from the expansion and
rotation values calculated for the substrate.